

Specification for Harmonized system of quality assessment for electronic components

Family specification

C. MOS digital integrated circuits
Series 4000 B and 4000 UB

Système harmonisé d'assurance de la qualité des composants électroniques Spécification de famille

Circuits integres digitaux C. MOS
Séries 4000 B et 4000 UB

Harmonisiertes Gütebestätigungssystem für Bauelemente der Elektronik Familien - Spezifikation

C. MOS Digitale integrierte Schaltungen
Serien 4000 B und 4000 UB

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Amendment No.1
published and effective from 15 August 1994
to BS CECC 90104 : 1990

Specification for harmonized system of
quality assessment for electronic components
Family specification: C.MOS digital integrated
circuits, series 4000 B and 4000 UB

NOTE. This amendment implements Amendment No.1 to CECC 90104, Issue 2 (1990). The national foreword has been amended accordingly.

Revised text

National foreword

In line 6, after the title of CECC 90104, insert 'as amended by Amendment No.1 published in 1994'.

AMD 8290/August 1994

Instructions for the insertion of new and revised pages

Delete pages 13/14 and substitute revised pages 13/14.

AMD 8290/August 1994

Delete pages 15 to 22 entirely.

AMD 8290/August 1994

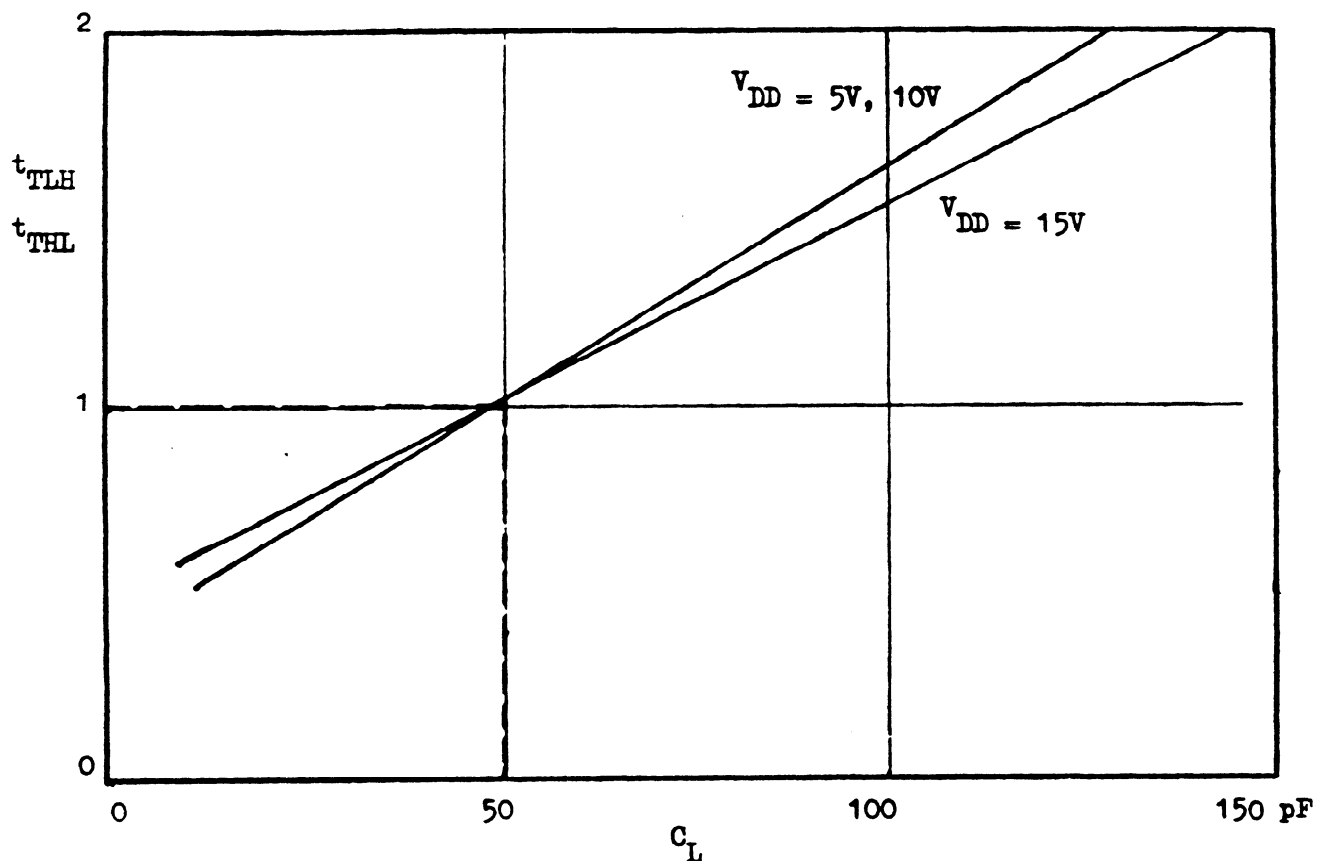
2.14.4 Variation of switching times with load capacitance shall be given in the detail specification.

Due to the very low input current requirements for C.MOS, there is practically no DC output loading capability limitation when driving other C.MOS inputs.

The actual fan-out of the C.MOS device is limited by a capacitance load consideration based on the desired system operating frequency.

The effects of capacitive load on the dynamic characteristics shall be given.

The curves shown below give the general trend of transition times versus load capacitance, which implies the general trend of propagation times versus load capacitance.



Normalized to $C_L = 50$ pF value

3 INSPECTION REQUIREMENTS

See 3.6 of CECC 90 000 with the following special requirements:

EXAMINATION OR TEST	D ND	CONDITIONS OF TEST	LIMITS TO BE SPECIFIED
GROUP A INSPECTION			
<u>Sub-Group A5</u> Dynamic characteristics at 25 °C See SS/4.1.3	ND	See FS/2.13 and relevant DS	See relevant DS
GROUP B INSPECTION			
<u>Sub-Group B5</u> Electrical endurance 168 h. See GS/note 11 See SS/4.2 End point tests: See GS/note 10 Electrical tests: Sub-Groups A2 and A3	ND	T _{amb} = 125 °C See SS/4.2.2 As for Sub-Groups A2 and A3	As for Sub-Groups A2 and A3
GROUP C INSPECTION			
<u>Sub-Group C8</u> Electrical endurance 2 000 h. See SS/4.2 End point tests: See GS/note 10 Electrical tests: Sub-Groups A2 and A3	ND	T _{amb} = 125 °C See SS/4.2.2 As for Sub-Groups A2 and A3	As for Sub-Groups A2 and A3
GROUP D INSPECTION			
<u>Sub-Group D1</u> Electrical endurance 8 000 h. See SS/4.2 End point tests: Electrical tests: Sub-Groups A2, A3 and A5	D	T _{amb} = 125 °C See SS/4.2.2 As for Sub-Groups A2, A3 and A5	As for Sub-Groups A2, A3 and A5

BS CECC 90104 : 1990

National foreword

This British Standard has been prepared under the direction of the Electronic Components Standards Policy Committee. It is identical with CENELEC Electronic Components Committee (CECC) 90104 : 1990 'Harmonized system of quality assessment for electronic components. Family specification : C.MOS digital integrated circuits. Series 4000 B and 4000 UB'.

This standard is a harmonized specification within the CECC system.

BS CECC 90104 : 1981 remains valid for existing qualification approvals until further notice.

Cross-references. The British Standard which implements CECC 00100 is BS 9000 'General requirements for a system for electronic components of assessed quality' Part 2 : 1983 'Specification for national implementation of CECC basic rules and rules of procedure'.

International standard*
IEC 68-2-30 : 1980

Corresponding British Standard
BS 2011 Environmental testing
Part 2.1Db : 1981 Test Db and
guidance: Damp heat, cyclic (12 +
12 hour cycle)
(Identical)

CECC 90000 : 1985

BS CECC 90000 : 1985 Harmonized
system of quality assessment for
electronic components. Generic
specification: Monolithic
integrated circuits
(Identical)

CECC 90100 : 1986

BS CECC 90100 : 1986 Harmonized
system of quality assessment for
electronic components: Sectional
specification: Digital monolithic
integrated circuits
(Identical)

BS 3934 : 1965 and Addendum No. 6 to BS 3934 : 1965 are related British Standards to IEC 191-2.

Scope. This standard lists the ratings, characteristics and inspection requirements which shall be included as mandatory requirements in accordance with BS CECC 90100 in any detail specification for these devices.

Detail specification layout. The front page layout of detail specifications released to BS CECC family or blank detail specifications will be in accordance with BS 9000 Circular Letter No.15 Issue 8 1989.

Compliance with a British Standard does not of itself confer immunity from legal obligations.

* Undated in text.

Système Harmonisé d'Assurance de la Qualité
des Composants Electroniques

SPECIFICATION DE FAMILLE:

CIRCUITS INTEGRES DIGITAUX C. MOS

SERIES 4000 B ET 4000 UB

Harmonized System of Quality Assessment for
Electronic Components

FAMILY SPECIFICATION:

C. MOS DIGITAL INTEGRATED CIRCUITS

SERIES 4000 B AND 4000 UB

Harmonisiertes Gütebestätigungssystem für
Bauelemente der Elektronik

FAMILIENSPEZIFIKATION:

C. MOS DIGITALE INTEGRIERTE SCHALTUNGEN

SERIEN 4000 B UND 4000 UB



2 Edition
Issue
Ausgabe

CECC 90 104

1990



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